

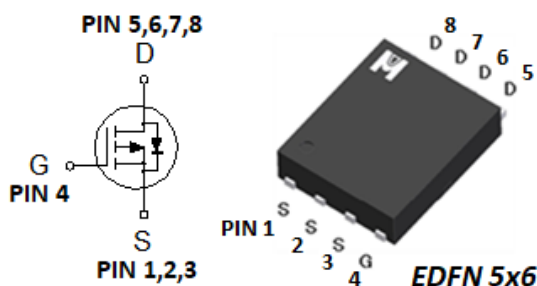
Single P-Channel Logic Level Enhancement Mode Field Effect Transistor
•Product Summary:

	P-CH
BVDSS	-30 V
$R_{DS(on) (MAX.) @ V_{GS} = -10V}$	2.5 mΩ
$R_{DS(on) (MAX.) @ V_{GS} = -4.5V}$	4.0 mΩ
$I_D @ T_C = 25^{\circ}C$	-230 A

Single P Channel MOSFET

UIS, Rg 100% Tested

RoHS & Halogen Free & TSCA Compliant

• Pin Description:

•ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 25	V
Continuous Drain Current	$T_C = 25^{\circ}C$	I_D	-230	A
	$T_C = 100^{\circ}C$		-146	
Continuous Drain Current	$T_A = 25^{\circ}C$	I_D	-24	
	$T_A = 70^{\circ}C$		-19	
Pulsed Drain Current ¹		I_{DM}	-453	
Avalanche Current		I_{AS}	-90	mJ
Avalanche Energy	$L = 0.1mH$	EAS	405	
Repetitive Avalanche Energy ²	$L = 0.05mH$	EAR	202.5	
Power Dissipation	$T_C = 25^{\circ}C$	P_D	201.6	W
	$T_C = 100^{\circ}C$		80.6	
Power Dissipation	$T_A = 25^{\circ}C$	P_D	2.4	W
	$T_A = 70^{\circ}C$		1.5	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	$^{\circ}C$

• 100% UIS testing in condition of $V_D = 25V$, $L = 0.1mH$, $V_G = 10V$, $I_L = 54A$, $R_G = 25\Omega$, Rated $V_{DS} = -30V$ P-CH

•THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case		$R_{\theta JC}$		0.62	$^{\circ}C/W$
Junction-to-Ambient ³	$t \leq 10s$	$R_{\theta JA}$		19	
	Steady-State	$R_{\theta JA}$		53	

¹ Pulse width limited by maximum junction temperature.

² Duty cycle $< 1\%$

³ The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^{\circ}C$.

⁴ Guarantee by Engineering test



▪ ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^{\circ}\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage ⁴	V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-30			V
Gate Threshold Voltage ⁴	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-1.2	-1.6	-2.5	
Gate-Body Leakage ⁴	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
		V _{DS} = 0V, V _{GS} = ±25V			±500	
Zero Gate Voltage Drain Current ⁴	I _{DSS}	V _{DS} = -30V, V _{GS} = 0V			-1	μA
		V _{DS} = -30V, V _{GS} = 0V, T _J = 125 °C			-25	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = -5V, V _{GS} = -10V	-230			A
Drain-Source On-State Resistance ^{1,4}	R _{DS(ON)}	V _{GS} = -10V, I _D = -25A		2.2	2.5	mΩ
		V _{GS} = -4.5V, I _D = -20A		3.0	4.0	
Forward Transconductance ¹	g _{fs}	V _{DS} = -5V, I _D = -25A		110		S
DYNAMIC						
Input Capacitance ⁵	C _{iss}	V _{GS} = 0V, V _{DS} = -15V, f = 1MHz		9280		pF
Output Capacitance ⁵	C _{oss}			1290		
Reverse Transfer Capacitance ⁵	C _{rss}			758		
Gate Resistance ^{4,5}	R _g	f = 1MHz		2.6		Ω
Total Gate Charge ^{1,2,5}	Q _g (V _{GS} =-10V)	V _{DS} = -15V, V _{GS} = 10V, I _D = -25A		178		nC
	Q _g (V _{GS} =-4.5V)			91		
Gate-Source Charge ^{1,2,5}	Q _{gs}			28		
Gate-Drain Charge ^{1,2,5}	Q _{gd}			42		
Turn-On Delay Time ^{1,2,5}	t _{d(on)}	V _{DS} = -15V, V _{GS} = -10V, I _D = -5A , R _g = 3Ω		10		nS
Rise Time ^{1,2,5}	t _r			18		
Turn-Off Delay Time ^{1,2,5}	t _{d(off)}			189		
Fall Time ^{1,2,5}	t _f			100		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Continuous Current	I _S				-230	A
Pulsed Current ³	I _{SM}				-453	
Forward Voltage ^{1,4}	V _{SD}	I _F = 25A, V _{GS} = 0V			-1.2	V
Reverse Recovery Time ⁵	t _{rr}	I _F = 25A, dI _F /dt = 100A / μS		26		nS
Peak Reverse Recovery Current ⁵	I _{RM(REC)}			1.1		A
Reverse Recovery Charge ⁵	Q _{rr}			16		nC

¹Pulse test : Pulse Width $\leq 300\text{ }\mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

⁴Guarantee by FT test Item

⁵Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



•TYPICAL CHARACTERISTICS

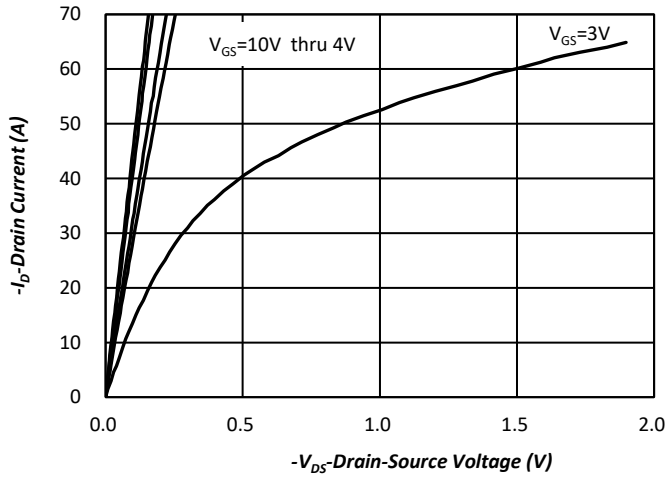


Fig.1 Typical Output Characteristics

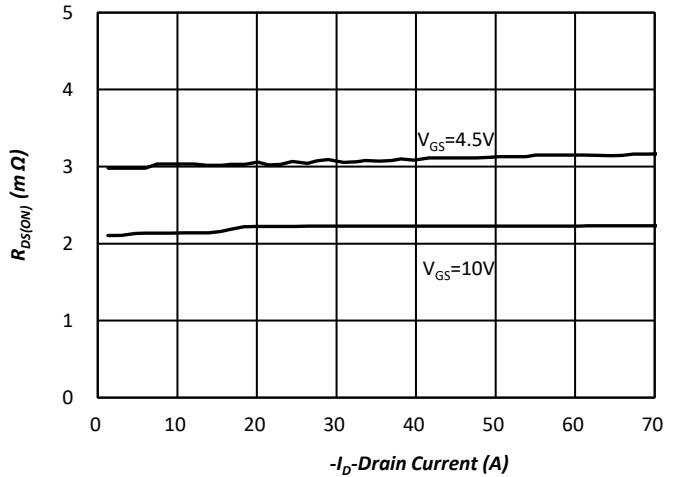


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

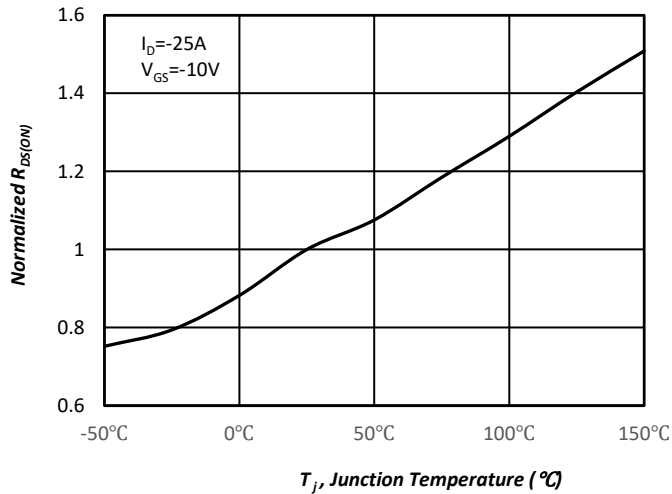


Fig.3 Normalized On-Resistance v.s. Junction Temperature

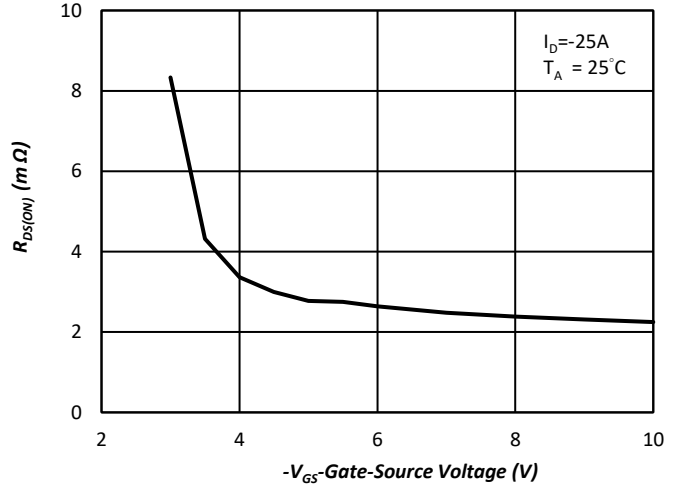


Fig.4 On-Resistance v.s. Gate Voltage

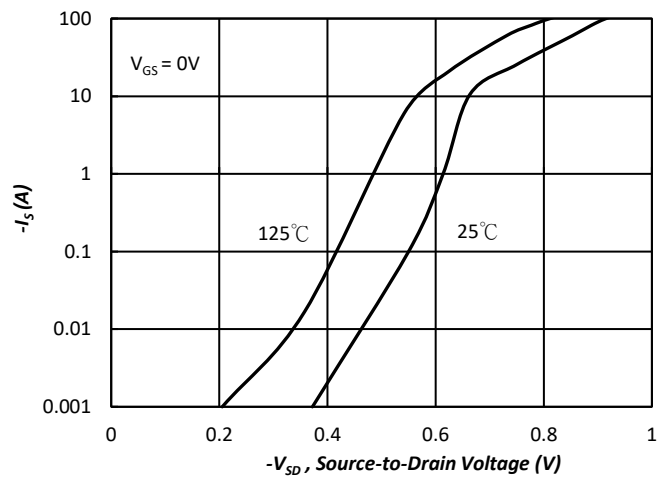


Fig.5 Forward Characteristic of Reverse Diode

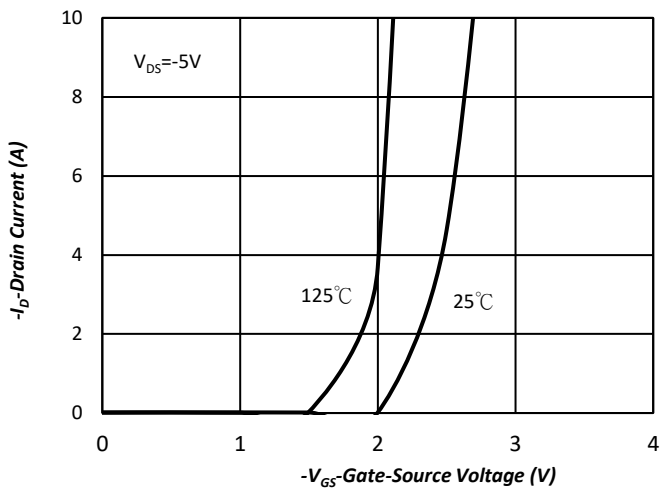


Fig.6 Transfer Characteristics

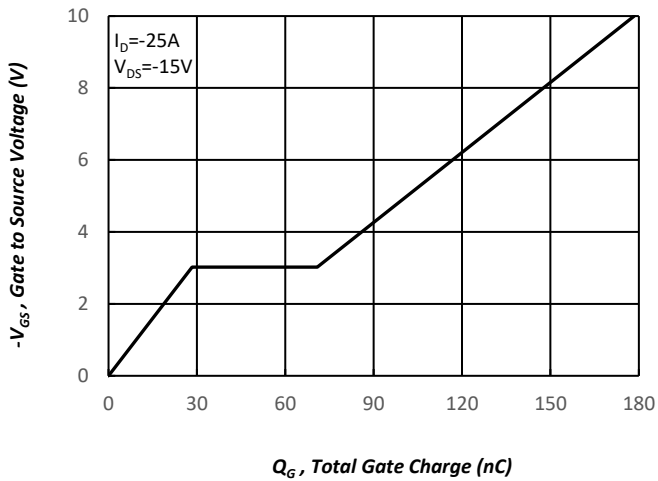


Fig.7 Gate Charge Characteristics

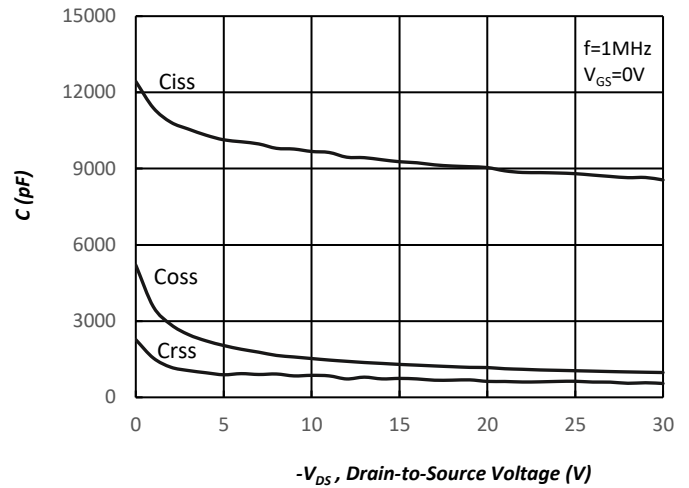


Fig.8 Typical Capacitance Characteristics

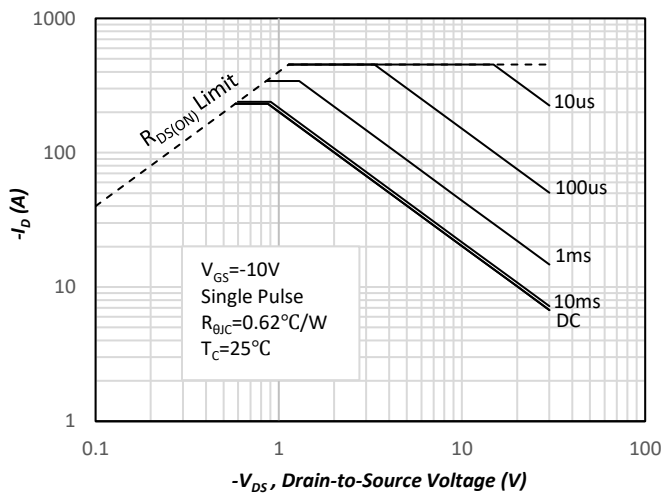


Fig.9. Maximum Safe Operating Area

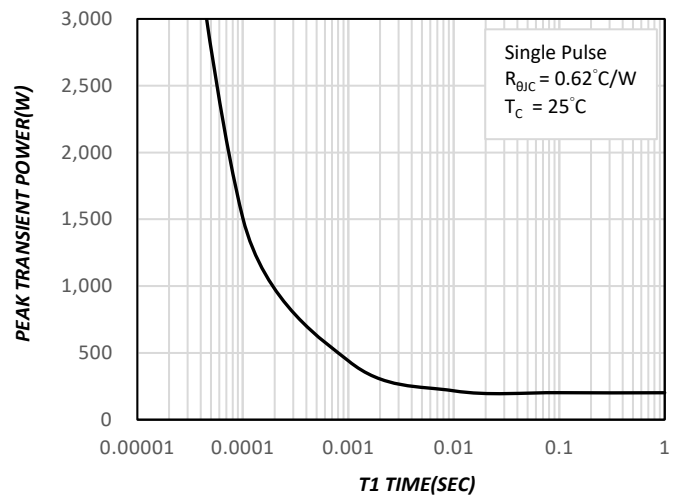


Fig.10. Single Pulse Maximum Power Dissipation

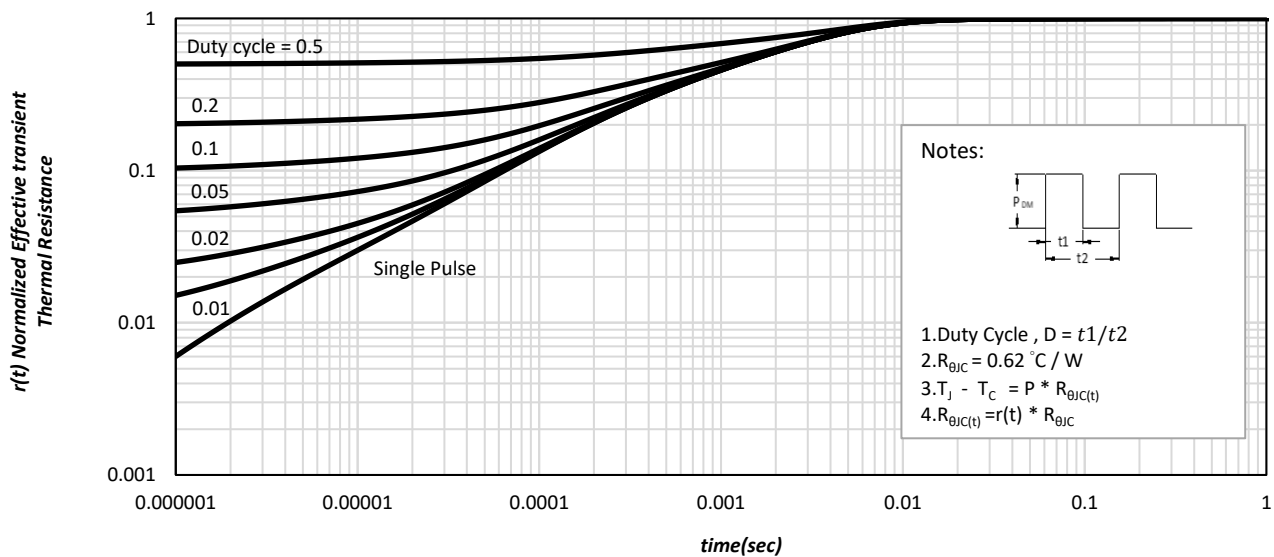
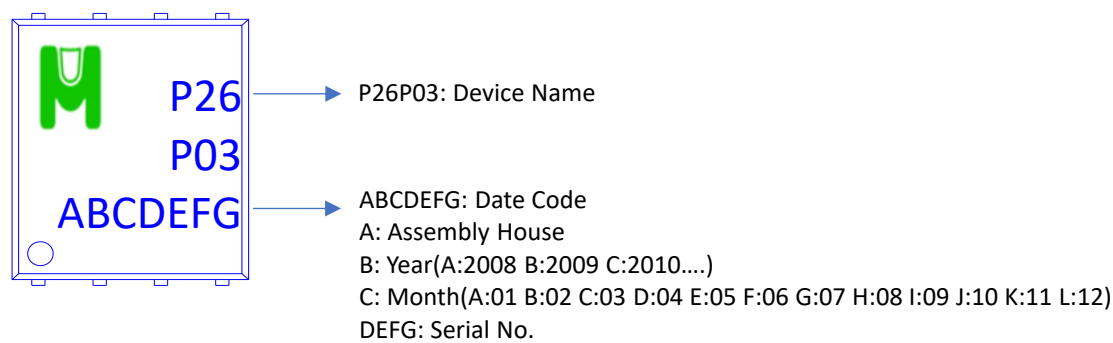


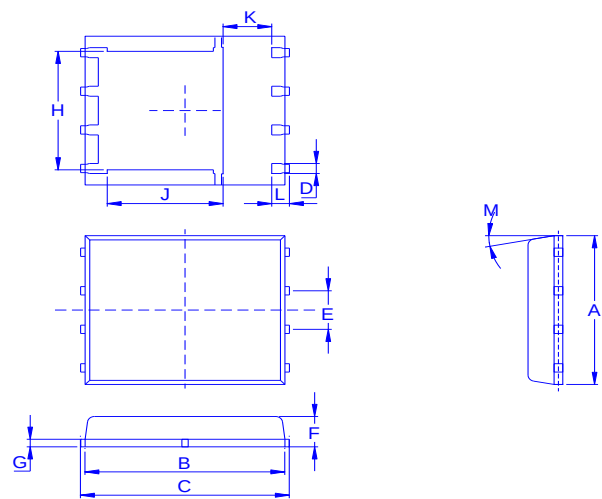
Fig.11. Effective Transient Thermal Impedance

Ordering & Marking Information:

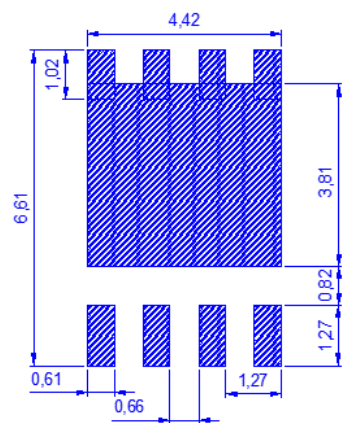
Device Name:EMP26P03H for EDFN 5x6



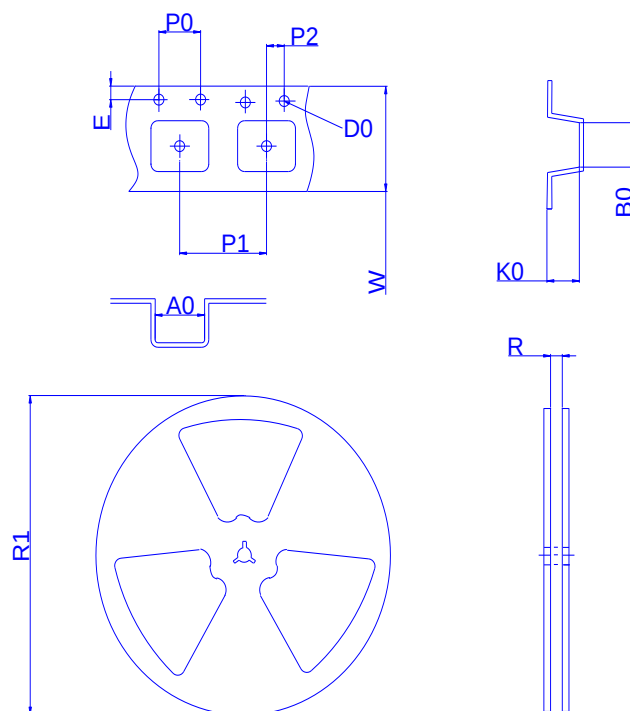
Outline Drawing



Dimension	A	B	C	D	E	F	G	H	J	K	L	M
Min.	4.8	5.55	5.9	0.3	1.17	0.85	0.15	3.61	3.18	1	0.38	0°
Typ.	4.9	5.7	6	0.4	1.27	0.95	0.2	3.87	3.44	1.2	0.4	
Max.	5.4	5.85	6.15	0.51	1.37	1.17	0.34	4.31	3.78	1.39	0.71	12°



◆ Tape&Reel Information:2500pcs/Reel(Dimension in millimeter)



Package	EDFN5X6
Reel	13"
Device orientation	FEED DIRECTION

Dimension in mm

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	6.4	5.3	1.5	1.8	1.6	4	8	2	12	12.4	330
±	0.2	0.2	0.1	0.1	0.6	0.1	0.1	0.1	0.3	2	2